



TECHNICAL SPECIFICATION



**Nanomanufacturing – Key control characteristics –
Part 2-4: Carbon nanotube materials – Test methods for determination
of resistance of individual carbon nanotubes**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

ICS 07.030; 07.120

ISBN 978-2-8322-7968-7

Warning! Make sure that you obtained this publication from an authorized distributor.

CONTENTS

FOREWORD.....	3
INTRODUCTION.....	5
1 Scope.....	6
2 Normative references	6
3 Terms, definitions, and abbreviated terms	6
3.1 Terms and definitions.....	6
3.2 Abbreviated terms.....	8
4 Measurement of resistance.....	8
4.1 General.....	8
4.2 Method for processing and fabrication of DUT.....	8
4.3 4-probe measurement.....	8
5 Reporting data.....	9
6 Data analysis / interpretation of results (Annex A)	10
6.1 General.....	10
6.2 Measurement error	10
6.3 Need to prepare the proper electric probing circuit.....	11
6.4 Need to prepare the proper substrate and electric contact	11
6.5 Dynamic range.....	11
6.6 Current density	11
6.7 Voltage bias of the substrate.....	11
6.8 Measurement in vacuum	11
Annex A (informative) Case study	12
A.1 4-probe measurement of MWCNT	12
A.1.1 I - V measurements of MWCNT.....	12
A.1.2 Fabrication process information of MWCNT and DUT	14
A.2 4-probe measurement of SWCNT.....	15
A.2.1 I - V measurements of SWCNT	15
A.2.2 Fabrication process information of SWCNT and DUT	18
Bibliography.....	19
Figure 1 – 4-probe measurement in a SEM chamber.....	9
Figure 2 – A crooked/curved CNT under measurement	10
Figure 3 – I - V measurement of a sufficiently straight CNT.....	11
Figure A.1 – I - V measurements of a CNT with different lengths, L	12
Figure A.2 – I - V relationships for different CNT lengths – 2-probe measurement.....	13
Figure A.3 – I - V relationships for different CNT lengths – 2-probe measurement (0 to 0,5 V)	13
Figure A.4 – I - V relationships for different CNT lengths – 4-probe measurement.....	14
Figure A.5 – Resistance vs. CNT length.....	14
Figure A.6 – I - V relationships of SWCNT	15
Figure A.7 – Resistance vs. SWCNT length	16
Figure A.8 – I - V relationships of SWCNT under the electron-beam exposure	17
Figure A.9 – Breakdown characteristics of SWCNT	18

INTERNATIONAL ELECTROTECHNICAL COMMISSION

NANOMANUFACTURING – KEY CONTROL CHARACTERISTICS –

Part 2-4: Carbon nanotube materials – Test methods for determination of resistance of individual carbon nanotubes

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

The main task of IEC technical committees is to prepare International Standards. In exceptional circumstances, a technical committee may propose the publication of a Technical Specification when

- the required support cannot be obtained for the publication of an International Standard, despite repeated efforts, or
- the subject is still under technical development or where, for any other reason, there is the future but no immediate possibility of an agreement on an International Standard.

Technical Specifications are subject to review within three years of publication to decide whether they can be transformed into International Standards.

IEC TS 62607-2-4, which is a Technical Specification, has been prepared by IEC technical committee 113: Nanotechnology for electrotechnical products and systems.

The text of this Technical Specification is based on the following documents:

DTS	Report on voting
113/492/DTS	113/509/RVDTS

Full information on the voting for the approval of this Technical Specification can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62607 series, published under the general title *Nanomanufacturing – Key control characteristics*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

INTRODUCTION

Carbon nanotubes (CNTs) are one-dimensional conductors that exhibit a rich variety of low-dimensional electric transport phenomena. Ballistic conduction is the typical nano-enabled characteristic that possesses the largest potential for industrial application. In the field of nanoelectronics, for example, CNT-based interconnects are a promising alternative to conventional Cu interconnects. However, even in the academic research society, the resistive characteristics have not yet been systematically investigated. This is because these characteristics are very sensitive to the protocol and the measurement conditions. Furthermore, since the individual CNT reaches the nanometre dimension, the contact resistance has a larger relative impact on the measurement. These bottlenecks impede not only the above-mentioned interconnect application but also developments of various electrotechnical applications, such as thermoelectric devices in which the electrical resistance is required to evaluate the figure of merit.

This document offers the accurate and reproducible test method for determining the resistance of CNT and the dependability of the measurement.

NANOMANUFACTURING – KEY CONTROL CHARACTERISTICS –

Part 2-4: Carbon nanotube materials – Test methods for determination of resistance of individual carbon nanotubes

1 Scope

This part of IEC 62607 specifies the test method for determining the resistivity and the contact resistance of an individual CNT and the dependability of the measurement.

This document includes:

- outlines of the experimental procedures used to measure resistance of carbon nanotubes,
- methods of interpretation of results and discussion of data analysis, and
- case studies.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 62624, *Test methods for measurement of electrical properties of carbon nanotubes*

ISO/TS 80004-1, *Nanotechnologies – Vocabulary – Part 1: Core terms*

NOTE IEC 62624 describes the general procedures for characterization of CNT. For example, no environmental condition is specifically required. On the other hand, this document focuses not only on the characterization of the individual CNT but also the reproducibility. To obtain the intrinsic nano-originated result and to measure up to the dependable measurement, in-vacuum non-destructive measurements are indispensable, and therefore this document (IEC TS 62607-2-4) is required.